FORM PTO-1449/A and B (Modified)				APPLICATION NO	D.: 10/763,819	ATTY. DOCKET NO.: H0498.70130US01	
	RMATION I			FILING DATE:	January 23, 2004	CONFIRMATION NO.: Not yet assigned	
STATEMENT BY APPLICANT			LICANT	APPLICANT:	Tao Deng et al.		
Sheet	1	of	2	- GROUP ART UNIT	T: Not yet assigned	EXAMINER: Not yet assigned	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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FILING DATE: January 5,2001 1/23/04

APPLICANT: Tao Deng et al.

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GROUP ART UNIT: Not Yet Assigned EXAMINER: Not Yet Assigned

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#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

^{*}a copy of this reference is not provided as it was previously cited by or submitted to the office in a prior application, Serial No. 09/755,645, filed January 5, 2001, and relied upon for an earlier filing date under 35 U.S.C. 120 (continuation, continuation-in-part, and divisional applications).